

Notice of References Cited

Application/Control No.

10/537,590

Applicant(s)/Patent Under
Reexamination
LIU ET AL.

Examiner

KENAN CEHIC

Art Unit

2416

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 01/47181	06-2001	Finland	Nakagawa, Tomohiro	H04L 12/00
	O					
	P					
	Q					
	R					
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	T					

NON-PATENT DOCUMENTS

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